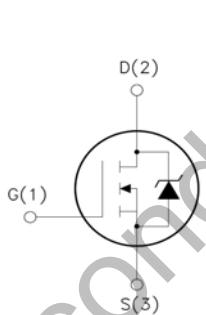


 WGD50N06S 60V N-Channel MOSFET	 TO-252   <p> 1. Gate (G) 2. Drain (D) 3. Source (S) </p>
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Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Maximum	Unit
V_{DSS}	Drain-to-Source Voltage	60	V
V_{GSS}	Gate-to-Source Voltage	± 25	V
I_D^3	Continuous Drain Current	$T_C=25^\circ\text{C}$	50
		$T_C=100^\circ\text{C}$	35
I_{DP}^4	Pulsed Drain Current	$T_C=25^\circ\text{C}$	200
I_{AS}^5	Avalanche Current	15	
E_{AS}^5	Avalanche energy	300	mJ
PD	Maximum Power Dissipation	$T_C=25^\circ\text{C}$	85
		$T_C=100^\circ\text{C}$	57
T_J, T_{STG}	Junction & Storage Temperature Range	-55~175	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	Typical	Unit
$R_{\theta jc}$	Thermal Resistance-Junction to Case	1.8	$^\circ\text{C}/\text{W}$
$R_{\theta ja}$	Thermal Resistance-Junction to Ambient	62.5	

Electrical Characteristics (TA=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ	Max.	Unit
Static Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	60	—	—	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =60V, V _{GS} =0V	—	—	1	uA
		T _J =125°C	—	—	100	
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250uA	1	—	3	V
I _{GSS}	Gate Leakage Current	V _{GS} =±25V, V _{DS} =0V	—	—	±100	nA
R _{DS(on)} ¹	Drain-Source On-Resistance	V _{GS} =10V, I _D =25A	—	—	20	mΩ
		—	—	—	—	
Diode Characteristics						
V _{SD} ¹	Diode Forward Voltage	I _{SD} =20A, V _{GS} =0V	—	0.8	1.2	V
I _S ³	Diode Continuous Forward Current	—	—	50	—	A
t _{rr}	Reverse Recovery Time	I _F =20A, dI/dt=100A/u	—	28	—	nS
Q _{rr}	Reverse Recovery Charge		—	40	—	nC
Dynamic Characteristics ²						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =30V Frequency=1MHz	—	2050	—	pF
C _{oss}	Output Capacitance		—	158	—	
C _{rss}	Reverse Transfer Capacitance		—	120	—	
t _{d(on)}	Turn-On Delay Time	V _{DD} =30V, I _D =25A, V _{GS} =10V, R _G =3Ω	—	7.4	—	nS
t _r	Rise Time		—	5.1	—	
t _{d(off)}	Turn-Off Delay Time		—	28.2	—	
t _f	Fall Time		—	5.5	—	
Gate Charge Characteristics ²						
Q _g	Total Gate Charge	V _{DS} =48V, V _{GS} =10V I _D =25A	—	50	—	nC
Q _{gs}	Gate-to-Source Charge		—	6.0	—	
Q _{gd}	Gate-to-Drain Charge		—	15	—	

Note: 1: Pulse test; pulse width \leq 300us, duty cycle \leq 2%.

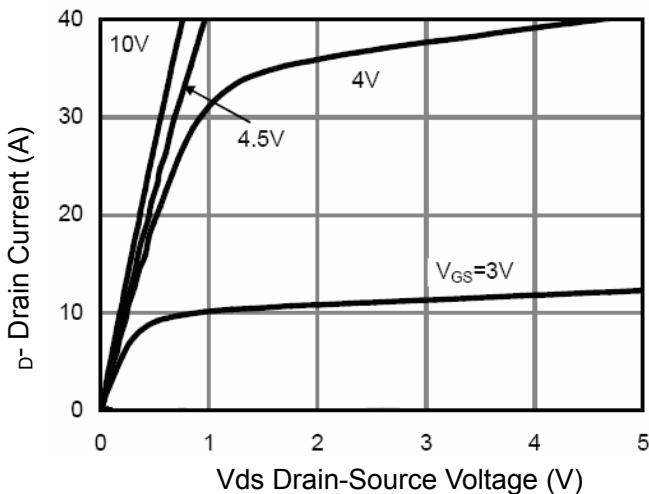
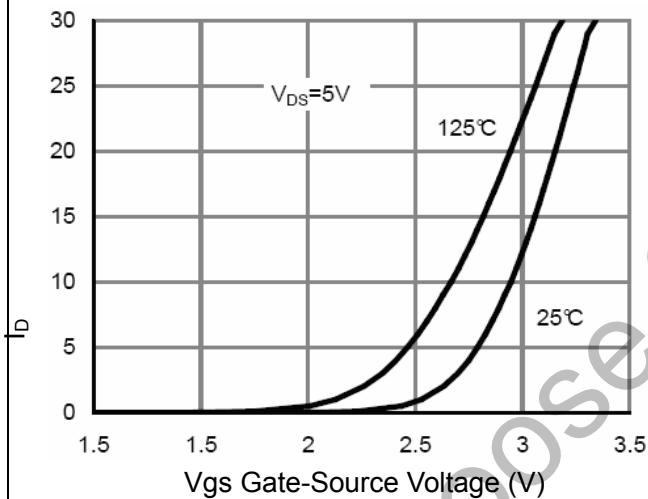
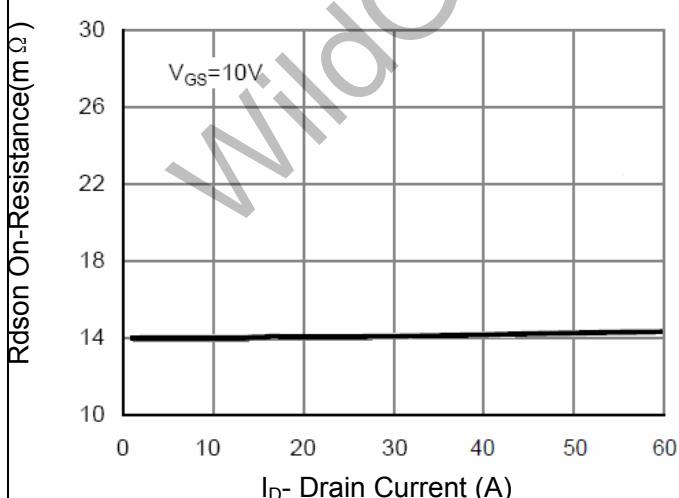
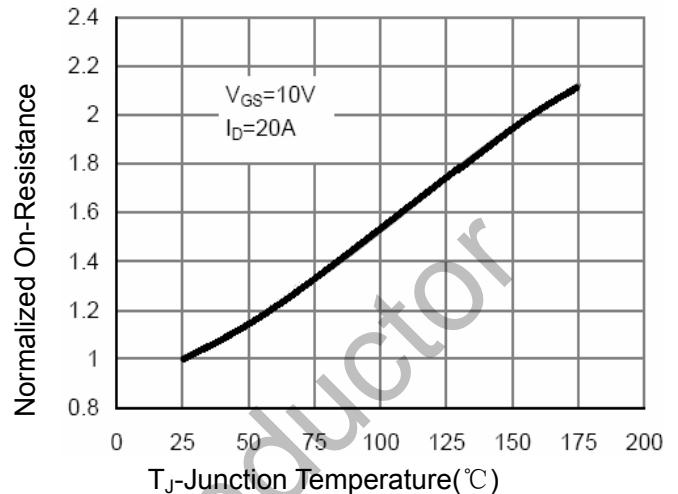
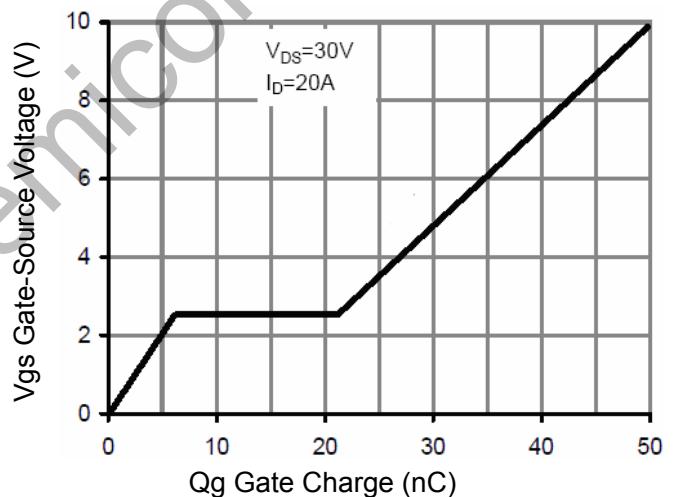
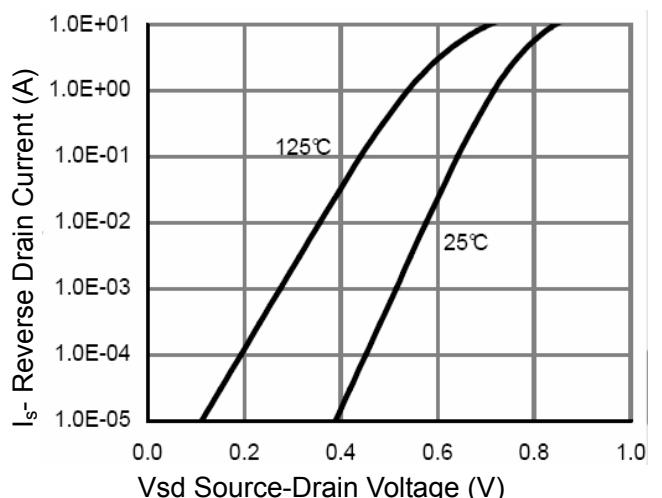
2: Guaranteed by design, not subject to production testing.

3: Package limitation current is 50A.Calculated continuous current based on maximum allowable junction temperature.

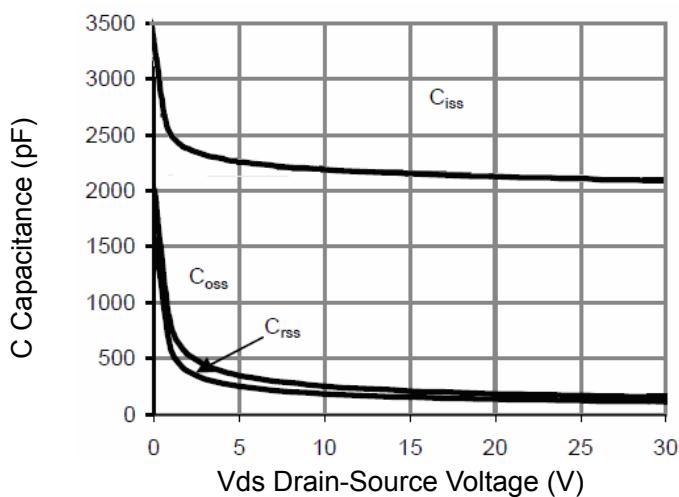
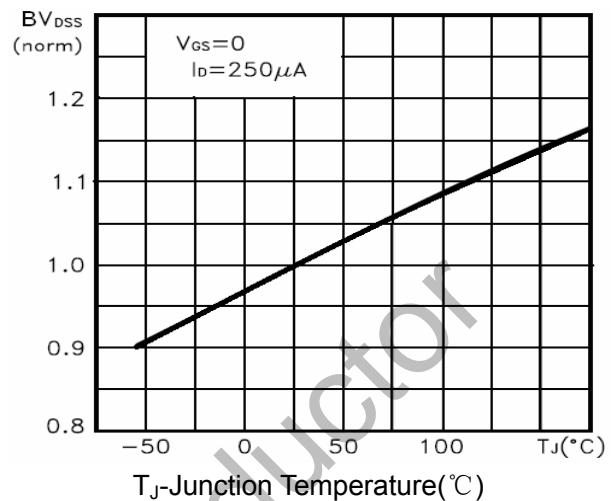
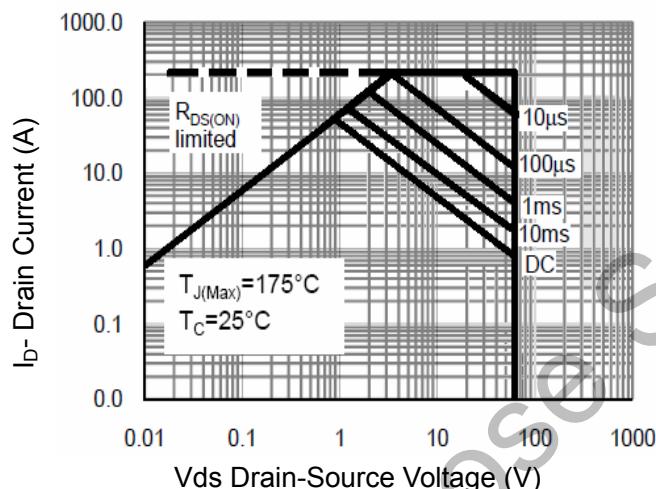
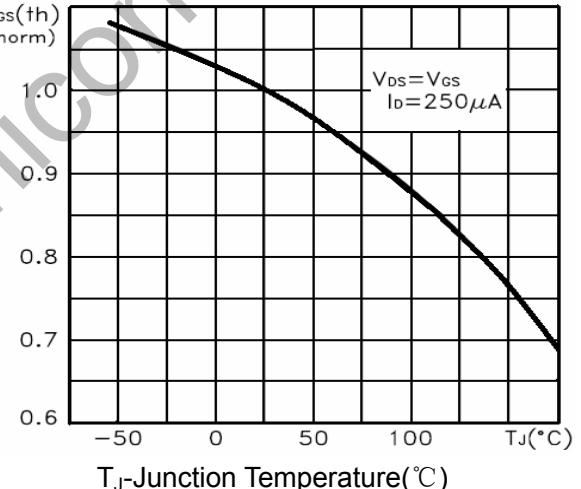
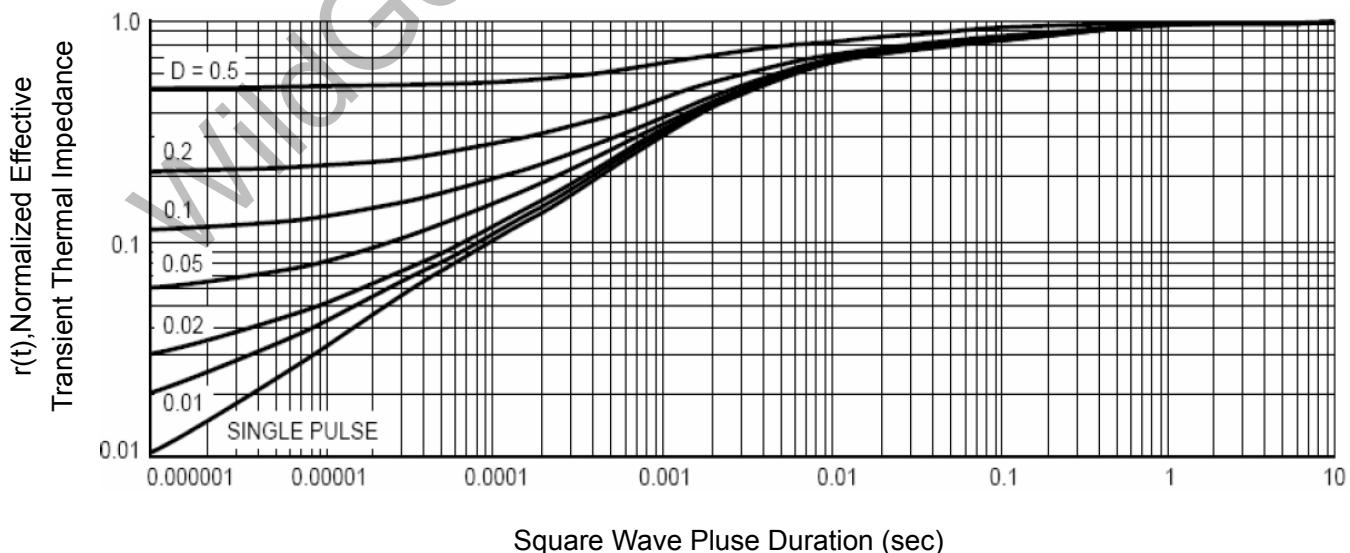
4: Repetitive rating, pulse width limited by max junction temperature.

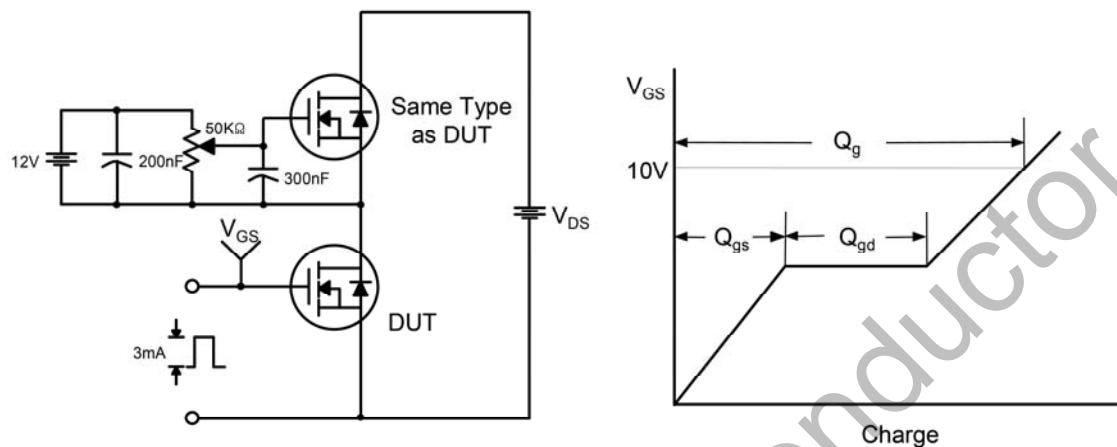
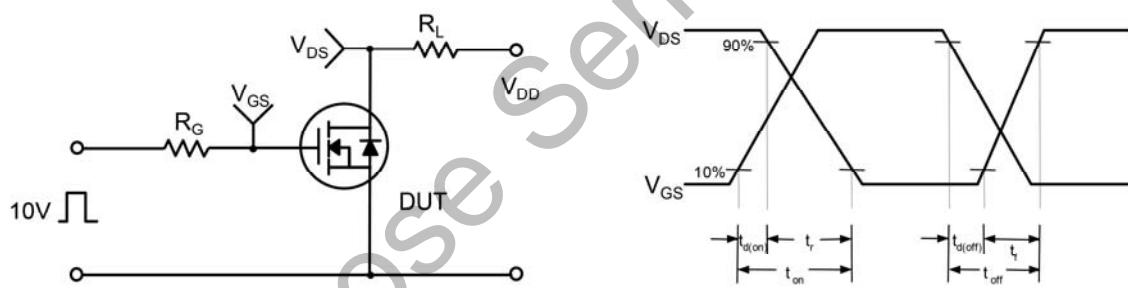
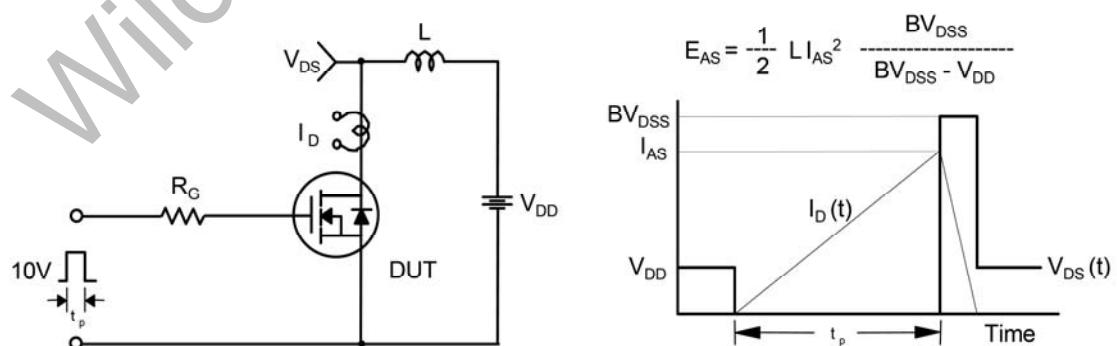
5: Starting TJ = 25°C,L = 0.5mH,IAS = 31A.

Typical Characteristics

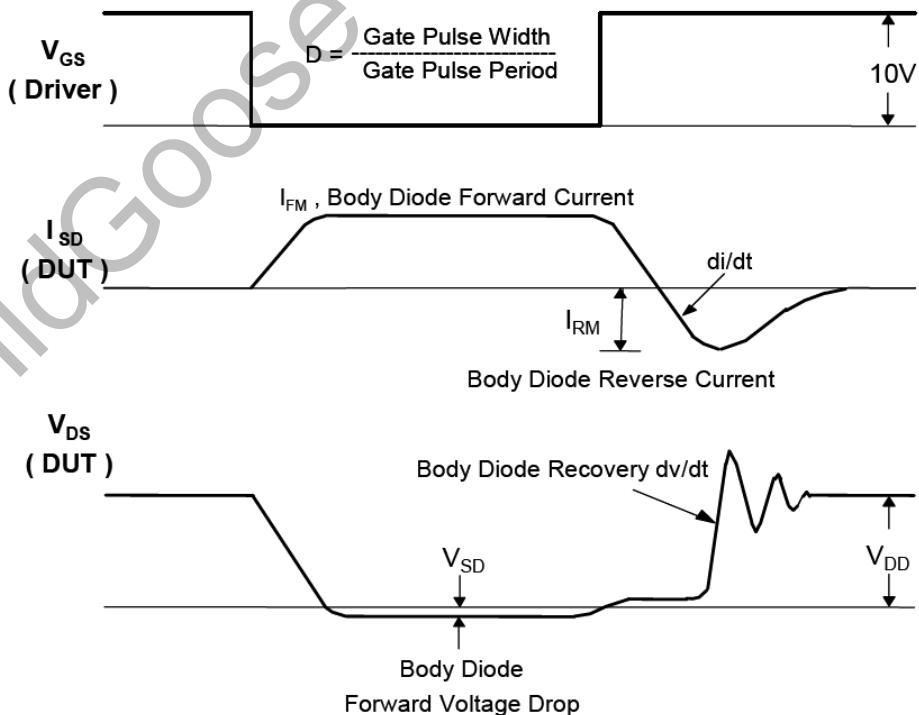
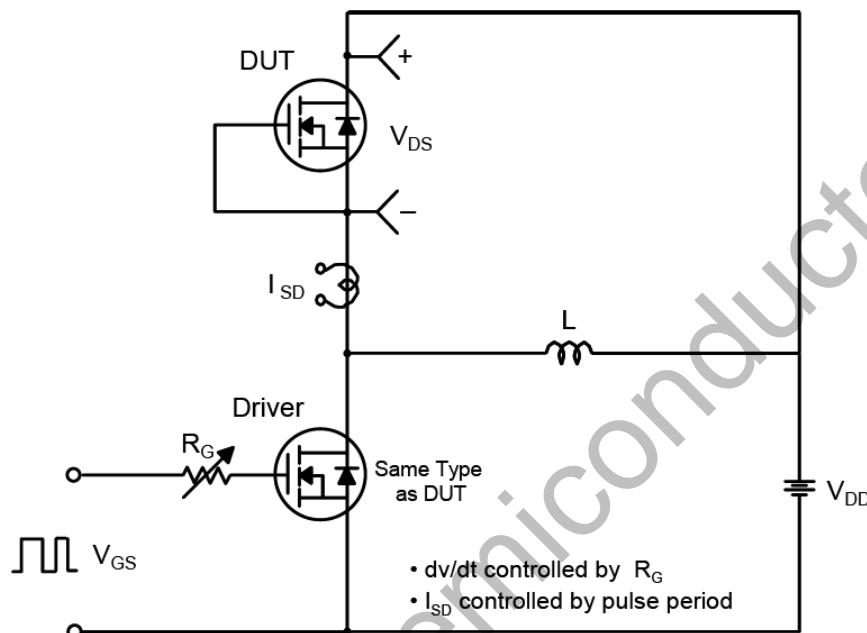
**Figure 1 Output Characteristics****Figure 2 Transfer Characteristics****Figure 3 Rdson- Drain Current****Figure 4 Rdson-Junction Temperature****Figure 5 Gate Charge****Figure 6 Source- Drain Diode Forward**

Typical Characteristics (Continued)

**Figure 7 Capacitance vs Vds****Figure 9 BV_{DSS} vs Junction Temperature****Figure 8 Safe Operation Area****Figure 10 $V_{GS(\text{th})}$ vs Junction Temperature****Figure 11 Normalized Maximum Transient Thermal Impedance**

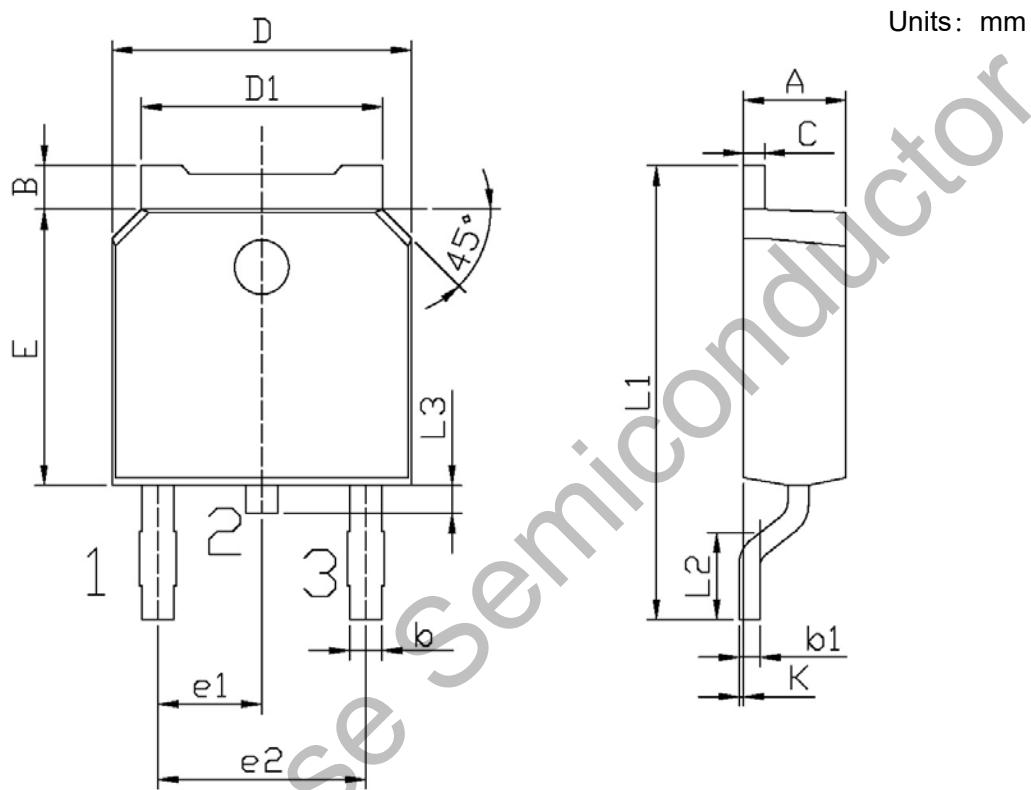
Gate Charge Test Circuit & Waveform**Resistive Switching Test Circuit & Waveforms****Unclamped Inductive Switching Test Circuit & Waveforms**

Peak Diode Recovery dv/dt Test Circuit & Waveform



Package Dimension

TO-252



Symbol	Dimensions In Millimeters		Symbol	Dimensions In Millimeters	
	Min	Max		Min	Max
A	2.20	2.40	E	5.95	6.25
B	0.95	1.25	e1	2.24	2.34
b	0.70	0.90	e2	4.43	4.73
b1	0.45	0.55	L1	9.85	10.35
C	0.45	0.55	L2	1.25	1.75
D	6.45	6.75	L3	0.60	0.90
D1	5.20	5.40	K	0.00	0.10